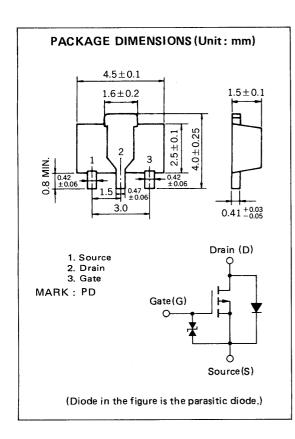


MOS FIELD EFFECT TRANSISTOR **2SJ205**

P-CHANNEL MOS FET FOR SWITCHING



The 2SJ205, P-channel vertical type MOS FET, is a switching device which can be driven by 3 V power supply.

As the MOS FET is driven by low voltage and does not require consideration of driving current, it is suitable for appliances including VCR cameras and headphone stereos which need power saving.

FEATURES

- Directly driven by ICs having a 3 V power supply.
- Not necessary to consider driving current because of its high input impedance,
- Possible to reduce the number of parts by omitting the bias resistor.
- Has low on-state resistance

$$R_{DS(on)}$$
 = 5.0 Ω MAX. $@V_{GS}$ = -2.5 V, I_D = -10 mA
 $R_{DS(on)}$ = 3.0 Ω MAX. $@V_{GS}$ = -4 V, I_D = -300 mA

QUALITY GRADE

Standard

Please refer to "Quality grade on NEC Semiconductor Devices" (Document number IEI-1209) published by NEC Corporation to know the specification of quality grade on the devices and its recommended applications.

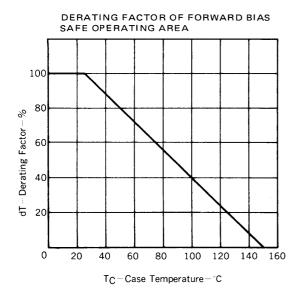
ABSOLUTE MAXIMUM RATINGS (Ta = 25 °C)

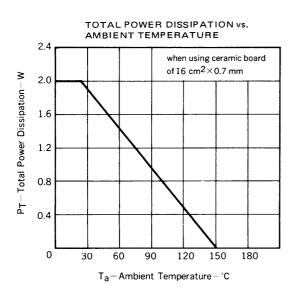
PARAMETER SYMBOL		RATINGS	UNIT	TEST CONDITIONS	
Drain to Source Voltage	V _{DSS}	-16	V	V _{GS} = 0	
Gate to Source Voltage	V _{GSS}	∓16	V	V _{DS} = 0	
Drain Current	ID(DC)	∓500	mA		
Drain Current	1 D(pulse)	∓1.0	А	PW ≦ 10 ms, Duty Cycle ≦ 50 %	
Total Power Dissipation	PT	2,0	w	When using ceramic board of 16 cm² x 0.7 mm	
Channel Temperature	T _{ch}	150	°C		
Operating Temperature	T _{opt}	-55 to +80	°C		
Storage Temperature	T _{stg}	-55 to +150	°C		

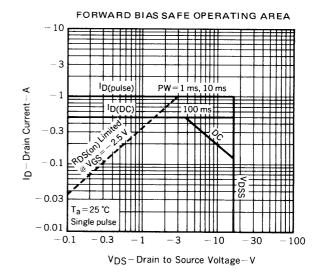
ELECTRICAL CHARACTERISTICS (T_a = 25 °C)

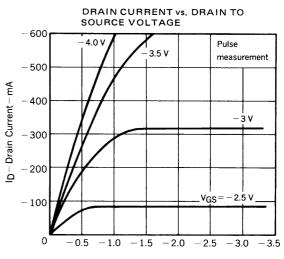
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS	
Drain Cut-off Current	IDSS			-1.0	μΑ	V _{DS} = -16 V, V _{GS} = 0	
Gate Leakage Current	IGSS			∓5	μΑ	V _{GS} = ∓16 V, V _{DS} = 0	
Gate Cut-off Voltage	V _{GS(off)}	-1.4	-1.9	-2.4	V	$V_{DS} = -5 \text{ V, I}_{D} = -10 \mu\text{A}$	
Forward Transfer Admittance	Yfs	0.4	0.5		S	$V_{DS} = -3 V, I_D = -0.3 A$	
Drain to Source On-State Resistance	R _{DS(on)1}		3,0	5.0	Ω	$V_{GS} = -2.5 \text{ V, I}_{D} = -10 \text{ mA}$	
Drain to Source On-State Resistance	RDS(on)2		1,5	3.0	Ω	$V_{GS} = -4 V, I_D = -0.3 A$	
Input Capacitance	C _{iss}		105		pF		
Output Capacitance	Coss		90		pF	$V_{DS} = -3.0 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	
Feedback Capacitance	C _{rss}		15		pF		
Turn-On Delay Time	td(on)		185		ns		
Rise Time	t _r		900		ns	$V_{GS(on)} = -3 \text{ V}, R_G = 10 \Omega, V_{DD} = -3 \text{ V},$	
Turn-Off Delay Time	td(off)		40		ns	$I_D = -0.3 \text{ A, R}_L = 10 \Omega$	
Fall Time	tf		135		ns		

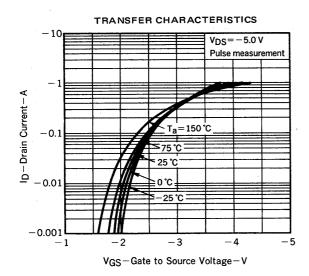
TYPICAL CHARACTERISTICS (T_a = 25 °C)

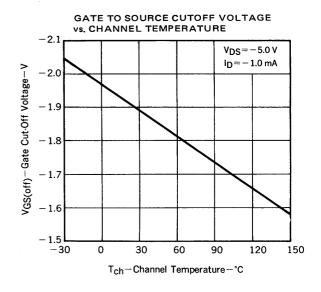


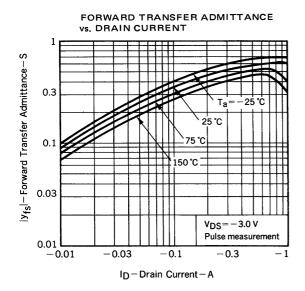


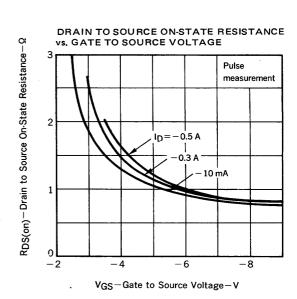


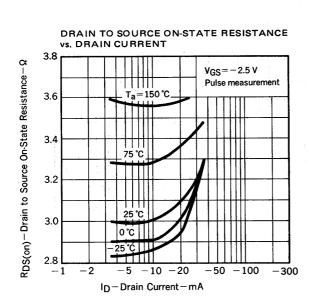


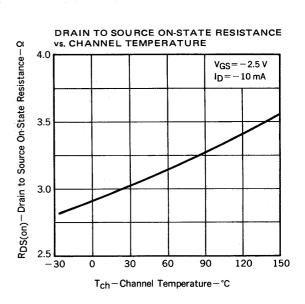


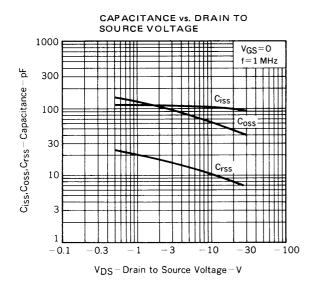


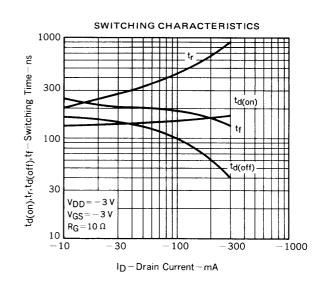


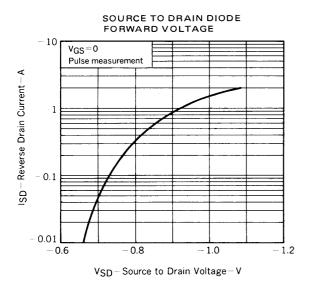




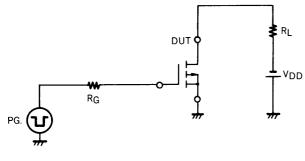




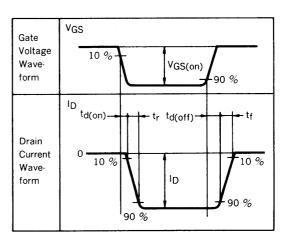




SWITCHING TIME MEASUREMENT CIRCUIT AND CONDITIONS









RECOMMENDED SOLDERING CONDITIONS

Mounting of this product by soldering should be done under the following conditions.

Please consult with our representatives about soldering methods and conditions other than these recommended.

SURFACE MOUNT TYPE

For details of the recommended soldering conditions, see the information document.

"Device Mounting Manual for Surface Mounting (IEI-1207)."

Soldering Method	Soldering Conditions	Symbol for Recommended Conditions IR30-00	
Infrared Reflow	Package peak temp.: 230 °C Soldering time: within 30 sec (above 210°C) Soldering times: 1, Days limitation: none*		
Vapor Phase Soldering	Package peak temp.: 215 °C Soldering time: within 40 sec (above 200°C) Soldering times: 1, Days limitation: none*	VP15-00	
Wave Soldering	Soldering bath temp.: below 260 °C Soldering time: within 10 sec Soldering times: 1, Days limitation: none*	WS60-00	

^{*} Stored days under storage conditions at 25 $^{\circ}\text{C}$ and below 65 % R .H. after dry-pack opened.

Note 1: Combination of soldering methods should be avoided,

REFERENCE

Document Name	Document No.	
NEC semiconductor device reliability/quality control system.	TEI-1202	
Quality grade on NEC semiconductor devices.	IEI-1209	
Semiconductor device mounting technology manual.	IEI-1207	
Semiconductor device package manual.	IEI-1213	
Guide to quality assurance for semiconductor devices.	MEI-1202	
Semiconductor selection guide.	MF-1134	

(MEMO)

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Application examples recommended by NEC Corporation

Standard: Computer, Office equipment, Communication equipment, Test and Measurement equipment, Machine tools, Industrial robots, Audio and Visual equipment, Other consumer products, etc.

Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.

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